

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.  
MI22-1196

SERIAL NO.  
09/388,063

LIST OF ART CITED BY APPLICANT  
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FEB 12 2002

APPLICANT  
Ashnu K. Agarwal et al.

FILING DATE  
August 30, 1999

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2815

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,834,060	11-10-98	Kawahara et al.			
	AB	5,972,430	10-26-99	DiMeo, Jr. Et al.			
	AC	6,127,218	10-3-00	Kang			
	AD	6,277,436	8-21-01	Stauf et al.			
	AE	6,245,652	6-12-01	Gardner et al.			
	AF	6,126,753	10-3-00	Shinriki et al.			
	AG						
	AH						
	AI	09/652,907		Basceri et al.			8-31-00
	AJ	09/776,217		Basceri			2-2-01
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AR	C. Basceri et al., "The dielectric response as a function of temperature and film thickness of fiber-textured (Ba,Sr) TiO <sub>3</sub> thin films grown by chemical vapor deposition", 5/97, pp. 2497-2504.
AS	Basceri C. "Electrical and Dielectric Properties of (Ba,Sr)TiO <sub>3</sub> Thin Film Capacitors for Ultra-High Density Dynamic Random Access Memories", 1997, dissertation submitted to Graduate Faculty of N. Carolina State Univ., Dept. Of Materials Science and Engineering

EXAMINER *James L. Jentz* DATE CONSIDERED 12/11/00

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ATTY. DOCKET NO.  
M122-1196

SERIAL NO.  
09/388,063

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APPLICANT  
Vishnu K. Agarwal et al.

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per ms	AA 09/652,907		Basceri et al.			8-31-00
	AB 09/776,217		Basceri			2-2-01
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